Inventor: Hui-Chuan Hung

Serial No.: 10/656,754 Filed: 09/06/2003 For: In-Situ Electron Beam Induced Current Detection

Attorney Doc. No.: 67,200-1152

REPLACEMENT SHEET

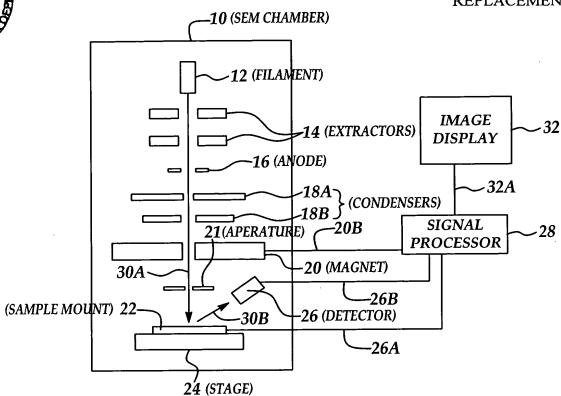


Figure 1

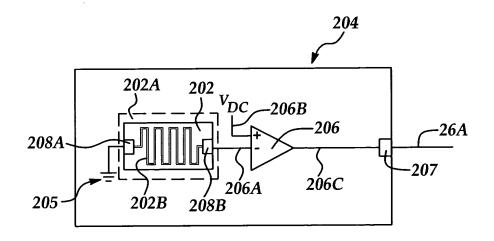


Figure 2A



Inventor: Hui-Chuan Hung Serial No.: 10/656,754 Filed: 09/06/2003 For: In-Situ Electron Beam Induced Current Detection

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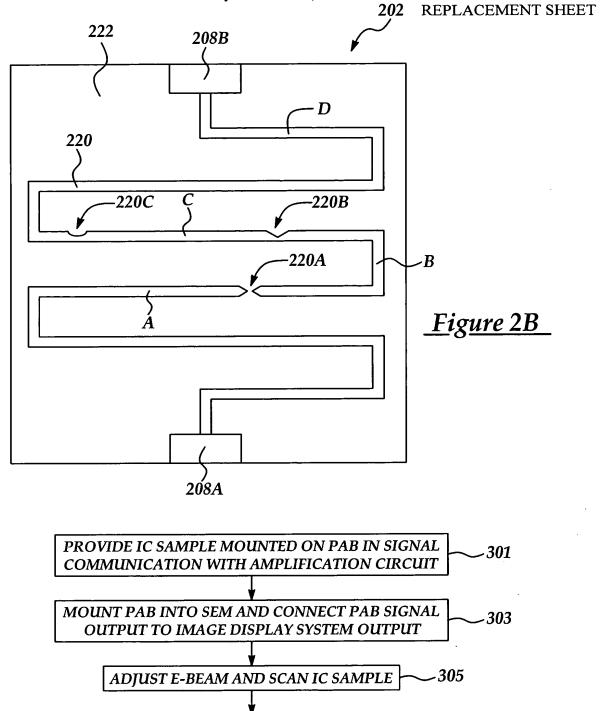


Figure 3

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PASS EBIC TO AMPLIFICATION ELECTRONICS AND TO IMAGE

DISPLAY SYSTEM TO PRODUCE CURRENT AND/OR RESISTANCE CONTRAST IMAGE